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Substitute for Form 1449A/PTO			<b>Complete if Known</b>		
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)			Application Number	10/625,993	
			Filing Date	Filed Herewith	
			First Named Inventor	Clark T.-C. Nguyen	
			Group Art Unit	2834	
			Examiner Name	T. Dougherty	
Sheet	1	of	3	Attorney Docket Number	UOM 0224 PUS 1

**U.S. PATENT DOCUMENTS**

Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	U.S. PATENT DOCUMENT		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code <sup>2</sup> (if known)			
td		4,081,769		Shreve	03/28/1978	
		4,262,269		Griffin, et al.	04/14/1981	
		4,596,969		Jachowski	06/24/1986	
		4,660,004		Jachowski	04/21/1987	
		4,721,925		Farace, et al.	01/26/1988	
		4,724,351		EerNisse, et al.	02/09/1988	
		4,862,122		Blair, Jr., et	08/29/1989	
		5,025,346		Tang, et al.	06/18/1991	
		5,065,119		Jachowski	11/12/1991	
		5,090,254		Guckel, et al.	2/25/1992	
		5,191,304		Jachowski	03/02/1993	
		5,399,232		Albrecht, et al.	03/21/1995	
		5,428,325		Jachowski, et al.	06/27/1995	
		5,446,729		Jachowski	08/29/1995	
		5,455,547		Lin, et al.	10/03/1995	
		5,491,604		Nguyen, et al.	02/13/1996	
		5,537,083		Lin, et al.	07/16/1996	
		5,550,516		Burns, et al.	08/27/1996	
		5,578,976		Yao	11/26/1996	
		5,589,082		Lin, et al.	12/31/1996	
		5,619,061		Goldsmith, et al.	04/08/1997	
		5,640,133		MacDonald, et al.	06/17/1997	
		5,783,973		Weinberg, et al.	07/21/1998	
		5,839,062		Nguyen, et al.	11/17/1998	
		5,872,489		Chang, et al.	02/16/1999	
		5,955,932		Nguyen, et al.	09/21/1999	
		5,963,857		Greywall	10/05/1999	
		5,976,994		Nguyen, et al.	11/02/1999	
		6,016,092		Qiu, et al.	01/18/2000	
		6,049,702		Tham, et al.	04/11/2000	
		6,169,321		Nguyen, et al.	01/02/2001	

**FOREIGN PATENT DOCUMENTS**

Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Foreign Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>3</sup>
		Office <sup>2</sup>	Number <sup>2</sup>				
td		EP	0 962 999 A2	Nokia Mobile Phones	12/08/1999		

Examiner Signature	<i>Thomas M. Dougherty</i>	Date Considered	2-17-05
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<sup>1</sup> EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>2</sup> Unique citation designation number. <sup>3</sup> See attached Kinds of U.S. Patent Documents. <sup>4</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>5</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document.

<sup>6</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>7</sup> Applicant is to place a check mark here if English language Translation is attached.

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FOREIGN PATENT DOCUMENTS									
Examiner Initials*	Cite No.¹	Foreign Patent Document			Kind Code² (If known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T³
		Office ³	Number ⁴						
<i>mg</i>		EP	0 962 999 A2			Nokia Mobile Phones	12/08/1999		

Examiner Signature	Thomas M. Hausher	Date Considered	2-17-05
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<sup>h</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>i</sup> Applicant is to place a check mark here if English language Translation is attached.

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			Group Art Unit	2834	
			Examiner Name	T. Dougherty	
Sheet	3	of	3	Attorney Docket Number	UOM 0224 PJS 1
<b>OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS</b>					
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T <sup>2</sup>
TMD		WONG, ARK-CHEW, ET AL., Micromechanical Mixer+Filters, Technical Digest, IEEE International Electron Devices Meeting, San Francisco, California, December 6-9, 1998, pp. 471-474			
TMD		NGUYEN, CLARK T.-C., et al., Design and Performance of CMOS Micromechanical Resonator Oscillators, IEEE International Frequency Control Symposium, 1994. pp. 127-134			
TMD		WANG, KUN, et al., Q-Enhancement of Microelectromechanical Filters Via Low-Velocity Spring Coupling, IEEE Ultrasonics Symposium, 1997, pp. 323-327			
TMD		BANNON, III, FRANK D., et al., High Frequency Microelectromechanical IF Filters, IEEE Electron Devices Meeting, 1996, pp. 30.4.1-30.4.4			
TMD		CLARK, JOHN R., et al., Parallel-Resonator HF Micromechanical Bandpass Filters, IEEE International Conference On Solid-State Sensors And Actuators, 1997, pp. 1161-1164			

Examiner Signature	<i>Thomas M. Dougherty</i>	Date Considered	2-17-05
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